

**Search Notes**

Application/Control No.

10/766,299

Examiner

Y. J. Han

**Applicant(s)/Patent under Reexamination**

ZVEREV ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	222		
	271		
	272		
	276		
	277		
	284		
	285		
	286		
	288		
	901		
	908		
363	49		
	50	1/06	JH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	1/06	JH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner